


<b>Search Notes</b>  	<b>Application/Control No.</b>  110578676	<b>Applicant(s)/Patent Under Reexamination</b>  TANEYA ET AL.
	<b>Examiner</b>  MARCOS BATISTA	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
455	566	11/4/2008	mb
455	575.3	4/16/2008	mb

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with TA - Yogesh Aggarwal	4/16/2008	mb
Consulted with Lun-YI Lao	4/16/2008	mb
East Search	4/16/2008	mb
Inventor's Name Seach	4/16/2008	mb
Consulted with Rafael Perez Gutierrez	11/4/2008	mb
Consulted with Rafael Perez Gutierrez	6/15/2009	mb

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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